

Abstract of the disclosure

A scanning probe microscope comprises scanning control means for controlling raster scanning of an XYZ translator, and displacement detection means for detecting amount of displacement of the XYZ translator, and is configured so that of the two raster scanning axes, only displacement of the XYZ translator along a low frequency scanning axis is feedback controlled, displacement of the XYZ translator along a high frequency scanning axis is made larger than a region to be observed, and sampling of an amount of displacement of the XYZ translator starts at the same time as a relative position of a probe enters into the observation region.